

## Scan Testable First-In First-Out Architecture

## ABSTRACT OF THE DISCLOSURE

[0027] An electronic device (10). The device comprises a memory structure (12), which comprises an integer  $M$  of memory word slots. Each memory word slot is operable to store an integer  $N$  of bits. The device also comprises a scan storage circuit (18), operable  
5 to receive a scan word having a number of bits less than  $M \times N$ . The device also comprises control circuitry (16) for causing successive scan words to be written into the scan storage circuit, for causing successive scan words to be written from the scan storage circuit into the memory structure, and for causing successive scan words to be read from the memory structure into the scan storage circuit.